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Surface chemical analysis - X-ray photoelectron spectroscopy - Procedures for assessing the day-to-day performan ce of an X-ray photoelectron spectrometer

Contents

Page

Foreword iv

Introduction v

1 Scope 1

2 Termsanddefinitions 1

3 Initial approach 1

4 Initial instrument calibration, alignment and assessment 1

5 Test specimen selection 2
5.1 General information 2
5.2 The conductive specimen 2
5.3 The non-conductive specimen 2
5.4 Specimen for assessing the X-ray source 4

6 Collection of reference data 4
6.1 General information 4
6.2 Rapid test of the instrument using a conductive specimen 4
6.3 Rapid test of the instrument using a non-conductive specimen 8
6.4 Rapid test of the X-ray source using a phosphor specimen 8
6.5 Rapid test of the X-ray source using a uniform conductive specimen 8

7 Collection of subsequent performance data 9

8 Analysis of the performance data 9
8.1 General information 9
8.2 Survey spectrum 9
8.3 High-resolution spectrum from the conductive specimen 10
8.4 High-resolution spectrum from the non-conductive specimen 10
8.5 Images from the phosphor specimen 10
8.6 Images from the uniform conductive specimen 10
8.7 Spectrum ratios 10

9 Control charts 15

Bibliography 18